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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	66MHz
Connectivity	CANbus, EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	118
Program Memory Size	768KB (768K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	82K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 24x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-144-4
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc228796f66lackxuma1

Table 1 XC228x Derivative Synopsis (cont'd)

Derivative[1)]	Temp. Range	Program Memory[2)]	PSRAM[3)]	CCU6 Mod.	ADC[4)] Chan.	Interfaces[4)]
SAK-XC2285-56FxxL	-40 °C to 125 °C	448 Kbytes Flash	16 Kbytes	0, 1	16	2 CAN Nodes, 4 Serial Chan.
SAF-XC2285-56FxxL	-40 °C to 85 °C	448 Kbytes Flash	16 Kbytes	0, 1	16	2 CAN Nodes, 4 Serial Chan.

1) This Data Sheet is valid for devices starting with and including design step AC.

2) Specific inormation about the on-chip Flash memory in **Table 2**.

3) All derivatives additionally provide 1 Kbyte SBRAM, 2 Kbytes DPRAM, and 16 Kbytes DSRAM.

4) Specific information about the available channels in **Table 3**.
Analog input channels are listed for each Analog/Digital Converter module separately (ADC0 + ADC1).

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
8	P7.0	O0 / I	St/B	**Bit 0 of Port 7, General Purpose Input/Output**
	T3OUT	O1	St/B	**GPT1 Timer T3 Toggle Latch Output**
	T6OUT	O2	St/B	**GPT2 Timer T6 Toggle Latch Output**
	TDO_A	OH	St/B	**JTAG Test Data Output**
	ESR2_1	I	St/B	**ESR2 Trigger Input 1**
	RxDC4B	I	St/B	**CAN Node 4 Receive Data Input**
9	P7.3	O0 / I	St/B	**Bit 3 of Port 7, General Purpose Input/Output**
	EMUX1	O1	St/B	**External Analog MUX Control Output 1 (ADC1)**
	U0C1_DOUT	O2	St/B	**USIC0 Channel 1 Shift Data Output**
	U0C0_DOUT	O3	St/B	**USIC0 Channel 0 Shift Data Output**
	CCU62_ CCPOS1A	I	St/B	**CCU62 Position Input 1**
	TMS_C	I	St/B	**JTAG Test Mode Selection Input**
	U0C1_DX0F	I	St/B	**USIC0 Channel 1 Shift Data Input**
10	P8.2	O0 / I	St/B	**Bit 2 of Port 8, General Purpose Input/Output**
	CCU60_ CC62	O1 / I	St/B	**CCU60 Channel 2 Input/Output**
11	P7.1	O0 / I	St/B	**Bit 1 of Port 7, General Purpose Input/Output**
	EXTCLK	O1	St/B	**Programmable Clock Signal Output**
	TxDC4	O2	St/B	**CAN Node 4 Transmit Data Output**
	CCU62_ CTRAPA	I	St/B	**CCU62 Emergency Trap Input**
	$\overline{\text{BRKIN\_C}}$	I	St/B	**OCDS Break Signal Input**

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
28	P15.7	I	In/A	**Bit 7 of Port 15, General Purpose Input**
	ADC1_CH7	I	In/A	**Analog Input Channel 7 for ADC1**
29	V_{AREF1}	-	PS/A	**Reference Voltage for A/D Converter ADC1**
30	V_{AREF0}	-	PS/A	**Reference Voltage for A/D Converter ADC0**
31	V_{AGND}	-	PS/A	**Reference Ground for A/D Converters ADC0/1**
32	P5.0	I	In/A	**Bit 0 of Port 5, General Purpose Input**
	ADC0_CH0	I	In/A	**Analog Input Channel 0 for ADC0**
33	P5.1	I	In/A	**Bit 1 of Port 5, General Purpose Input**
	ADC0_CH1	I	In/A	**Analog Input Channel 1 for ADC0**
34	P5.2	I	In/A	**Bit 2 of Port 5, General Purpose Input**
	ADC0_CH2	I	In/A	**Analog Input Channel 2 for ADC0**
	TDI_A	I	In/A	**JTAG Test Data Input**
35	P5.3	I	In/A	**Bit 3 of Port 5, General Purpose Input**
	ADC0_CH3	I	In/A	**Analog Input Channel 3 for ADC0**
	T3IN	I	In/A	**GPT1 Timer T3 Count/Gate Input**
39	P5.4	I	In/A	**Bit 4 of Port 5, General Purpose Input**
	ADC0_CH4	I	In/A	**Analog Input Channel 4 for ADC0**
	CCU63_ T12HRB	I	In/A	**External Run Control Input for T12 of CCU63**
	T3EUD	I	In/A	**GPT1 Timer T3 External Up/Down Control Input**
	TMS_A	I	In/A	**JTAG Test Mode Selection Input**
40	P5.5	I	In/A	**Bit 5 of Port 5, General Purpose Input**
	ADC0_CH5	I	In/A	**Analog Input Channel 5 for ADC0**
	CCU60_ T12HRB	I	In/A	**External Run Control Input for T12 of CCU60**
41	P5.6	I	In/A	**Bit 6 of Port 5, General Purpose Input**
	ADC0_CH6	I	In/A	**Analog Input Channel 6 for ADC0**
42	P5.7	I	In/A	**Bit 7 of Port 5, General Purpose Input**
	ADC0_CH7	I	In/A	**Analog Input Channel 7 for ADC0**

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
87	P0.3	O0 / I	St/B	**Bit 3 of Port 0, General Purpose Input/Output**
	U1C0_ SELO0	O1	St/B	**USIC1 Channel 0 Select/Control 0 Output**
	U1C1_ SELO1	O2	St/B	**USIC1 Channel 1 Select/Control 1 Output**
	CCU61_ COUT60	O3	St/B	**CCU61 Channel 0 Output**
	A3	OH	St/B	**External Bus Interface Address Line 3**
	U1C0_DX2A	I	St/B	**USIC1 Channel 0 Shift Control Input**
	RxDC0B	I	St/B	**CAN Node 0 Receive Data Input**
88	P3.1	O0 / I	St/B	**Bit 1 of Port 3, General Purpose Input/Output**
	U2C0_DOUT	O1	St/B	**USIC2 Channel 0 Shift Data Output**
	TxDC3	O2	St/B	**CAN Node 3 Transmit Data Output**
	HLDA	OH / I	St/B	**External Bus Hold Acknowledge Output/Input** Output in master mode, input in slave mode.
	U2C0_DX0B	I	St/B	**USIC2 Channel 0 Shift Data Input**
89	P10.2	O0 / I	St/B	**Bit 2 of Port 10, General Purpose Input/Output**
	U0C0_ SCLKOUT	O1	St/B	**USIC0 Channel 0 Shift Clock Output**
	CCU60_ CC62	O2 / I	St/B	**CCU60 Channel 2 Input/Output**
	AD2	OH / I	St/B	**External Bus Interface Address/Data Line 2**
	U0C0_DX1B	I	St/B	**USIC0 Channel 0 Shift Clock Input**
90	P0.4	O0 / I	St/B	**Bit 4 of Port 0, General Purpose Input/Output**
	U1C1_ SELO0	O1	St/B	**USIC1 Channel 1 Select/Control 0 Output**
	U1C0_ SELO1	O2	St/B	**USIC1 Channel 0 Select/Control 1 Output**
	CCU61_ COUT61	O3	St/B	**CCU61 Channel 1 Output**
	A4	OH	St/B	**External Bus Interface Address Line 4**
	U1C1_DX2A	I	St/B	**USIC1 Channel 1 Shift Control Input**
	RxDC1B	I	St/B	**CAN Node 1 Receive Data Input**

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
97	P3.3	O0 / I	St/B	**Bit 3 of Port 3, General Purpose Input/Output**
	U2C0_ SELO0	O1	St/B	**USIC2 Channel 0 Select/Control 0 Output**
	U2C1_ SELO1	O2	St/B	**USIC2 Channel 1 Select/Control 1 Output**
	U2C0_DX2A	I	St/B	**USIC2 Channel 0 Shift Control Input**
	RxDC3A	I	St/B	**CAN Node 3 Receive Data Input**
98	P10.4	O0 / I	St/B	**Bit 4 of Port 10, General Purpose Input/Output**
	U0C0_ SELO3	O1	St/B	**USIC0 Channel 0 Select/Control 3 Output**
	CCU60_ COUT61	O2	St/B	**CCU60 Channel 1 Output**
	AD4	OH / I	St/B	**External Bus Interface Address/Data Line 4**
	U0C0_DX2B	I	St/B	**USIC0 Channel 0 Shift Control Input**
	U0C1_DX2B	I	St/B	**USIC0 Channel 1 Shift Control Input**
99	P3.4	O0 / I	St/B	**Bit 4 of Port 3, General Purpose Input/Output**
	U2C1_ SELO0	O1	St/B	**USIC2 Channel 1 Select/Control 0 Output**
	U2C0_ SELO1	O2	St/B	**USIC2 Channel 0 Select/Control 1 Output**
	U0C0_ SELO4	O3	St/B	**USIC0 Channel 0 Select/Control 4 Output**
	U2C1_DX2A	I	St/B	**USIC2 Channel 1 Shift Control Input**
	RxDC4A	I	St/B	**CAN Node 4 Receive Data Input**
100	P10.5	O0 / I	St/B	**Bit 5 of Port 10, General Purpose Input/Output**
	U0C1_ SCLKOUT	O1	St/B	**USIC0 Channel 1 Shift Clock Output**
	CCU60_ COUT62	O2	St/B	**CCU60 Channel 2 Output**
	AD5	OH / I	St/B	**External Bus Interface Address/Data Line 5**
	U0C1_DX1B	I	St/B	**USIC0 Channel 1 Shift Clock Input**

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
122	P9.3	O0 / I	St/B	**Bit 3 of Port 9, General Purpose Input/Output**
	CCU63_ COUT60	O1	St/B	**CCU63 Channel 0 Output**
	$\overline{\text{BRKOUT}}$	O2	St/B	**OCDS Break Signal Output**
123	P10.13	O0 / I	St/B	**Bit 13 of Port 10, General Purpose Input/Output**
	U1C0_DOUT	O1	St/B	**USIC1 Channel 0 Shift Data Output**
	TxDC3	O2	St/B	**CAN Node 3 Transmit Data Output**
	U1C0_ SELO3	O3	St/B	**USIC1 Channel 0 Select/Control 3 Output**
	$\overline{\text{WR}}$/$\overline{\text{WRL}}$	OH	St/B	**External Bus Interface Write Strobe Output** Active for each external write access, when $\overline{\text{WR}}$, active for ext. writes to the low byte, when $\overline{\text{WRL}}$.
	U1C0_DX0D	I	St/B	**USIC1 Channel 0 Shift Data Input**
124	P1.3	O0 / I	St/B	**Bit 3 of Port 1, General Purpose Input/Output**
	CCU62_ COUT63	O1	St/B	**CCU62 Channel 3 Output**
	U1C0_ SELO7	O2	St/B	**USIC1 Channel 0 Select/Control 7 Output**
	U2C0_ SELO4	O3	St/B	**USIC2 Channel 0 Select/Control 4 Output**
	A11	OH	St/B	**External Bus Interface Address Line 11**
	ESR2_4	I	St/B	**ESR2 Trigger Input 4**
	CCU62_ T12HRB	I	St/B	**External Run Control Input for T12 of CCU62**
	EX3AINA	I	St/B	**External Interrupt Trigger Input**
125	P9.4	O0 / I	St/B	**Bit 4 of Port 9, General Purpose Input/Output**
	CCU63_ COUT61	O1	St/B	**CCU63 Channel 1 Output**
	U2C0_DOUT	O2	St/B	**USIC2 Channel 0 Shift Data Output**

3 Functional Description

The architecture of the XC228x combines advantages of RISC, CISC, and DSP processors with an advanced peripheral subsystem in a well-balanced design. On-chip memory blocks allow the design of compact systems-on-silicon with maximum performance suited for computing, control, and communication.

The on-chip memory blocks (program code memory and SRAM, dual-port RAM, data SRAM) and the generic peripherals are connected to the CPU by separate high-speed buses. Another bus, the LXBus, connects additional on-chip resources and external resources (see **Figure 3**). This bus structure enhances overall system performance by enabling the concurrent operation of several subsystems of the XC228x.

The block diagram gives an overview of the on-chip components and the advanced internal bus structure of the XC228x.

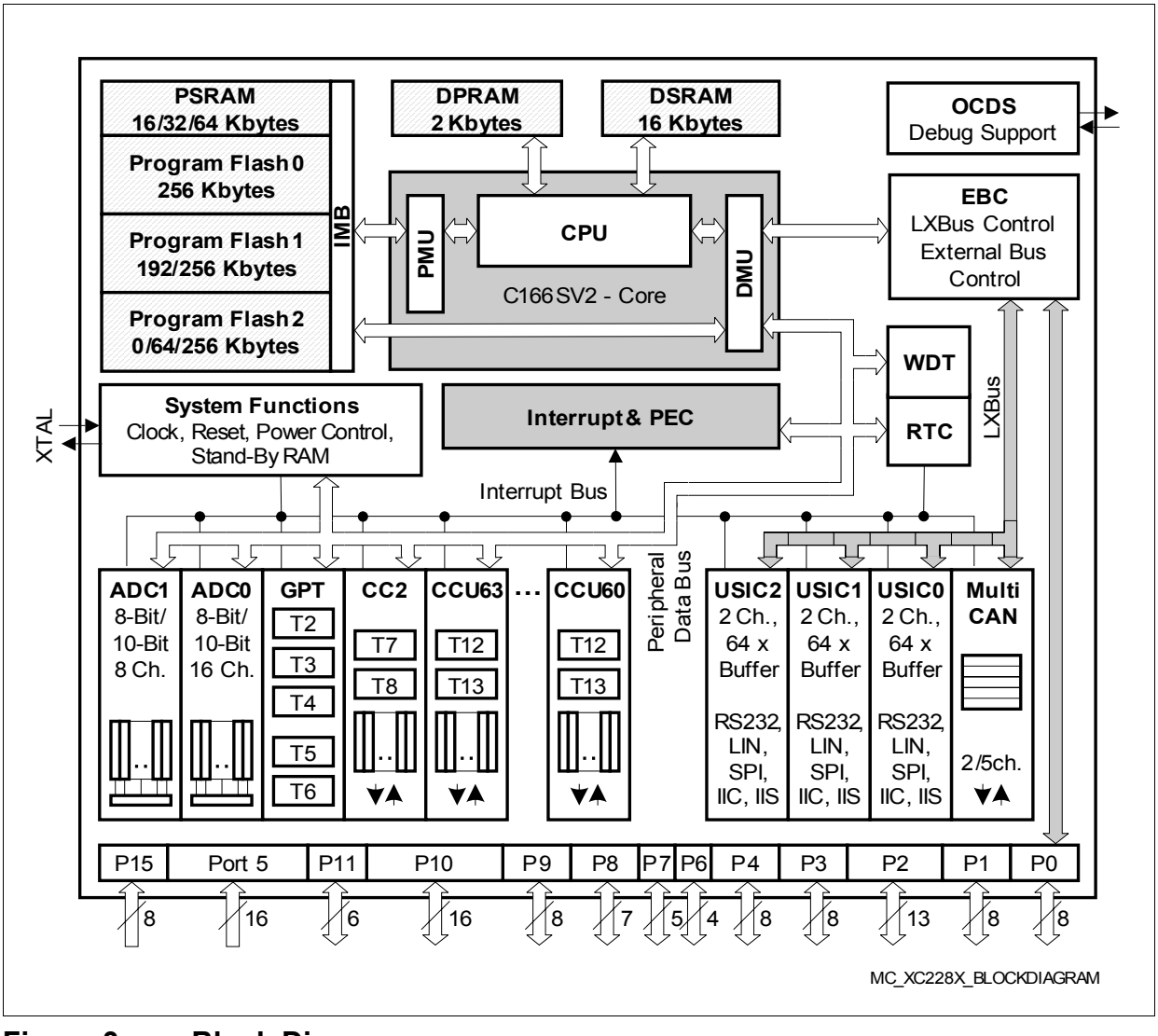

Figure 3 Block Diagram

When a capture/compare register has been selected for capture mode, the current contents of the allocated timer will be latched (‘captured’) into the capture/compare register in response to an external event at the port pin associated with this register. In addition, a specific interrupt request for this capture/compare register is generated. Either a positive, a negative, or both a positive and a negative external signal transition at the pin can be selected as the triggering event.

The contents of all registers selected for one of the five compare modes are continuously compared with the contents of the allocated timers.

When a match occurs between the timer value and the value in a capture/compare register, specific actions will be taken based on the compare mode selected.

The RTC module can be used for different purposes:

- System clock to determine the current time and date
- Cyclic time-based interrupt, to provide a system time tick independent of CPU frequency and other resources
- 48-bit timer for long-term measurements
- Alarm interrupt at a defined time

Table 10 Instruction Set Summary (cont'd)

Mnemonic	Description	Bytes
NOP	Null operation	2
CoMUL/CoMAC	Multiply (and accumulate)	4
CoADD/CoSUB	Add/Subtract	4
Co(A)SHR	(Arithmetic) Shift right	4
CoSHL	Shift left	4
CoLOAD/STORE	Load accumulator/Store MAC register	4
CoCMP	Compare	4
CoMAX/MIN	Maximum/Minimum	4
CoABS/CoRND	Absolute value/Round accumulator	4
CoMOV	Data move	4
CoNEG/NOP	Negate accumulator/Null operation	4

1) The Enter Power Down Mode instruction is not used in the XC228x, due to the enhanced power control scheme. PWRDN will be correctly decoded, but will trigger no action.

Table 12 Operating Condition Parameters (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
External Pin Load Capacitance	C_L	–	20	–	pF	Pin drivers in **default** mode[6]
Voltage Regulator Buffer Capacitance for DMP_M	C_{EVRM}	1.0	–	4.7	µF	[7]
Voltage Regulator Buffer Capacitance for DMP_1	C_{EVR1}	0.47	–	2.2	µF	One for each supply pin[7]
Operating frequency	f_{SYS}	–	–	80	MHz	[8]
Ambient temperature	T_A	–	–	–	°C	See **Table 1**

1) If both core power domains are clocked, the difference between the power supply voltages must be less than 10 mV. This condition imposes additional constraints when using external power supplies.
Do not combine internal and external supply of different core power domains.
Do not supply the core power domains with two independent external voltage regulators. The simplest method is to supply both power domains directly via a single external power supply.

2) Performance of pad drivers, A/D Converter, and Flash module depends on V_{DDP}.
If the external supply voltage V_{DDP} becomes lower than the specified operating range, a power reset must be generated. Otherwise, the core supply voltage V_{DDI} may rise above its specified operating range due to parasitic effects.
This power reset can be generated by the on-chip SWD. If the SWD is disabled the power reset must be generated by activating the $\overline{\text{PORST}}$ input.

3) Overload conditions occur if the standard operating conditions are exceeded, i.e. the voltage on any pin exceeds the specified range: $V_{OV} > V_{IHmax}$ ($I_{OV} > 0$) or $V_{OV} < V_{ILmin}$ ($I_{OV} < 0$). The absolute sum of input overload currents on all pins may not exceed **50 mA**. The supply voltages must remain within the specified limits. Proper operation under overload conditions depends on the application.
Overload conditions must not occur on pin XTAL1 (powered by V_{DDI}).

4) Not subject to production test - verified by design/characterization.

5) An overload current (I_{OV}) through a pin injects an error current (I_{INJ}) into the adjacent pins. This error current adds to that pin's leakage current (I_{OZ}). The value of the error current depends on the overload current and is defined by the overload coupling factor K_{OV}. The polarity of the injected error current is reversed from the polarity of the overload current that produces it.
The total current through a pin is $|I_{TOT}| = |I_{OZ}| + (|I_{OV}| \times K_{OV})$. The additional error current may distort the input voltage on analog inputs.

6) The timing is valid for pin drivers operating in default current mode (selected after reset). Reducing the output current may lead to increased delays or reduced driving capability (C_L).

7) To ensure the stability of the voltage regulators the EVRs must be buffered with ceramic capacitors. Separate buffer capacitors with the recomended values shall be connected as close as possible to each V_{DDI} pin to keep the resistance of the board tracks below 2 Ω. Connect all V_{DDI1} pins together.
The minimum capacitance value is required for proper operation under all conditions (e.g. temperature). Higher values slightly increase the startup time.

8) The operating frequency range may be reduced for specific types of the XC228x. This is indicated in the device designation (…FxxL). 80-MHz devices are marked …F80L.

4.2 DC Parameters

These parameters are static or average values that may be exceeded during switching transitions (e.g. output current).

The XC228x can operate within a wide supply voltage range from 3.0 V to 5.5 V. However, during operation this supply voltage must remain within 10 percent of the selected nominal supply voltage. It cannot vary across the full operating voltage range.

Because of the supply voltage restriction and because electrical behavior depends on the supply voltage, the parameters are specified separately for the upper and the lower voltage range.

During operation, the supply voltages may only change with a maximum speed of dV/dt < 1 V/ms.

Leakage current is strongly dependent on the operating temperature and the voltage level at the respective pin. The maximum values in the following tables apply under worst case conditions, i.e. maximum temperature and an input level equal to the supply voltage.
The value for the leakage current in an application can be determined by using the respective leakage derating formula (see tables) with values from that application.

The pads of the XC228x are designed to operate in various driver modes. The DC parameter specifications refer to the current limits in **Table 13**.

Table 13 Current Limits for Port Output Drivers

Port Output Driver Mode	Maximum Output Current (I_{OLmax}, $-I_{OHmax}$)[1]		Nominal Output Current (I_{OLnom}, $-I_{OHnom}$)	
	$V_{DDP} \geq$ 4.5 V	$V_{DDP} <$ 4.5 V	$V_{DDP} \geq$ 4.5 V	$V_{DDP} <$ 4.5 V
Strong driver	10 mA	10 mA	2.5 mA	2.5 mA
Medium driver	4.0 mA	2.5 mA	1.0 mA	1.0 mA
Weak driver	0.5 mA	0.5 mA	0.1 mA	0.1 mA

1) An output current above $|I_{OXnom}|$ may be drawn from up to three pins at the same time.
For any group of 16 neighboring output pins, the total output current in each direction (ΣI_{OL} and $\Sigma -I_{OH}$) must remain below 50 mA.

2) Not subject to production test - verified by design/characterization. Hysteresis is implemented to avoid metastable states and switching due to internal ground bounce. It cannot suppress switching due to external system noise under all conditions.
3) The maximum deliverable output current of a port driver depends on the selected output driver mode, see **Table 13, Current Limits for Port Output Drivers**. The limit for pin groups must be respected.
4) As a rule, with decreasing output current the output levels approach the respective supply level ($V_{OL} \rightarrow V_{SS}$, $V_{OH} \rightarrow V_{DDP}$). However, only the levels for nominal output currents are verified.
5) This specification is not valid for outputs which are switched to open drain mode. In this case the respective output will float and the voltage is determined by the external circuit.
6) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin. Please refer to the definition of the overload coupling factor K_{OV}.
7) The given values are worst-case values. In production test, this leakage current is only tested at 125°C; other values are ensured by correlation. For derating, please refer to the following descriptions:
   Leakage derating depending on temperature (T_J = junction temperature [°C]):
   I_{OZ} = 0.05 × $e^{(1.5 + 0.028 \times TJ)}$ [µA]. For example, at a temperature of 130°C the resulting leakage current is 8.54 µA.
   Leakage derating depending on voltage level (DV = V_{DDP} - V_{PIN} [V]):
   I_{OZ} = $I_{OZtempmax}$ - (1.6 × DV) [µA]
   This voltage derating formula is an approximation which applies for maximum temperature.
   Because pin P2.8 is connected to two pads (standard pad and high-speed clock pad), it has twice the normal leakage.
8) Keep current: Limit the current through this pin to the indicated value so that the enabled pull device can keep the default pin level: $V_{PIN} \geq V_{IH}$ for a pullup; $V_{PIN} \leq V_{IL}$ for a pulldown.
   Force current: Drive the indicated minimum current through this pin to change the default pin level driven by the enabled pull device: $V_{PIN} \leq V_{IL}$ for a pullup; $V_{PIN} \geq V_{IH}$ for a pulldown.
   These values apply to the fixed pull-devices in dedicated pins and to the user-selectable pull-devices in general purpose IO pins.
9) Not subject to production test - verified by design/characterization.
   Because pin P2.8 is connected to two pads (standard pad and high-speed clock pad), it has twice the normal capacitance.

2) Not subject to production test - verified by design/characterization. Hysteresis is implemented to avoid metastable states and switching due to internal ground bounce. It cannot suppress switching due to external system noise under all conditions.
3) The maximum deliverable output current of a port driver depends on the selected output driver mode, see **Table 13, Current Limits for Port Output Drivers**. The limit for pin groups must be respected.
4) As a rule, with decreasing output current the output levels approach the respective supply level ($V_{OL} \rightarrow V_{SS}$, $V_{OH} \rightarrow V_{DDP}$). However, only the levels for nominal output currents are verified.
5) This specification is not valid for outputs which are switched to open drain mode. In this case the respective output will float and the voltage is determined by the external circuit.
6) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin. Please refer to the definition of the overload coupling factor K_{OV}.
   The leakage current value is not tested in the lower voltage range but only in the upper voltage range. This parameter is ensured by correlation.
7) The given values are worst-case values. In production test, this leakage current is only tested at 125°C; other values are ensured by correlation. For derating, please refer to the following descriptions:
   Leakage derating depending on temperature (T_J = junction temperature [°C]):
   I_{OZ} = 0.03 × $e^{(1.35 + 0.028 \times TJ)}$ [µA]. For example, at a temperature of 130°C the resulting leakage current is 4.41 µA.
   Leakage derating depending on voltage level (DV = V_{DDP} - V_{PIN} [V]):
   I_{OZ} = $I_{OZtempmax}$ - (1.3 × DV) [µA]
   This voltage derating formula is an approximation which applies for maximum temperature.
   Because pin P2.8 is connected to two pads (standard pad and high-speed clock pad), it has twice the normal leakage.
8) Keep current: Limit the current through this pin to the indicated value so that the enabled pull device can keep the default pin level: $V_{PIN} \geq V_{IH}$ for a pullup; $V_{PIN} \leq V_{IL}$ for a pulldown.
   Force current: Drive the indicated minimum current through this pin to change the default pin level driven by the enabled pull device: $V_{PIN} \leq V_{IL}$ for a pullup; $V_{PIN} \geq V_{IH}$ for a pulldown.
   These values apply to the fixed pull-devices in dedicated pins and to the user-selectable pull-devices in general purpose IO pins.
9) Not subject to production test - verified by design/characterization.
   Because pin P2.8 is connected to two pads (standard pad and high-speed clock pad), it has twice the normal capacitance.

Table 17 Leakage Power Consumption XC228x (Operating Conditions apply)

Parameter	Sym-bol	Values			Unit	Note / Test Condition[1]
		Min.	Typ.	Max.		
Leakage supply current[2] (DMP_1 powered) Formula[3]: 600,000 × $e^{-\alpha}$; α = 5000 / (273 + B×T_J); Typ.: B = 1.0, Max.: B = 1.3	I_{LK1}	–	0.03	0.05	mA	T_J = 25°C
		–	0.5	1.3	mA	T_J = 85°C
		–	2.1	6.2	mA	T_J = 125°C
		–	4.4	13.7	mA	T_J = 150°C
Leakage supply current[2] (DMP_1 off) Formula[3]: 500,000 × $e^{-\alpha}$; α = 3000 / (273 + B×T_J); Typ.: B = 1.0, Max.: B = 1.6	I_{LK0}	–	20	35	µA	T_J = 25°C
		–	115	330	µA	T_J = 85°C
		–	270	880	µA	T_J = 125°C
		–	420	1,450	µA	T_J = 150°C

1) All inputs (including pins configured as inputs) are set at 0 V to 0.1 V or at V_{DDP} - 0.1 V to V_{DDP} and all outputs (including pins configured as outputs) are disconnected.

2) The supply current caused by leakage depends mainly on the junction temperature (see **Figure 14**) and the supply voltage. The temperature difference between the junction temperature T_J and the ambient temperature T_A must be taken into account. As this fraction of the supply current does not depend on device activity, it must be added to other power consumption values.

3) This formula is valid for temperatures above 0°C. For temperatures below 0°C a value of below 10 µA can be assumed.

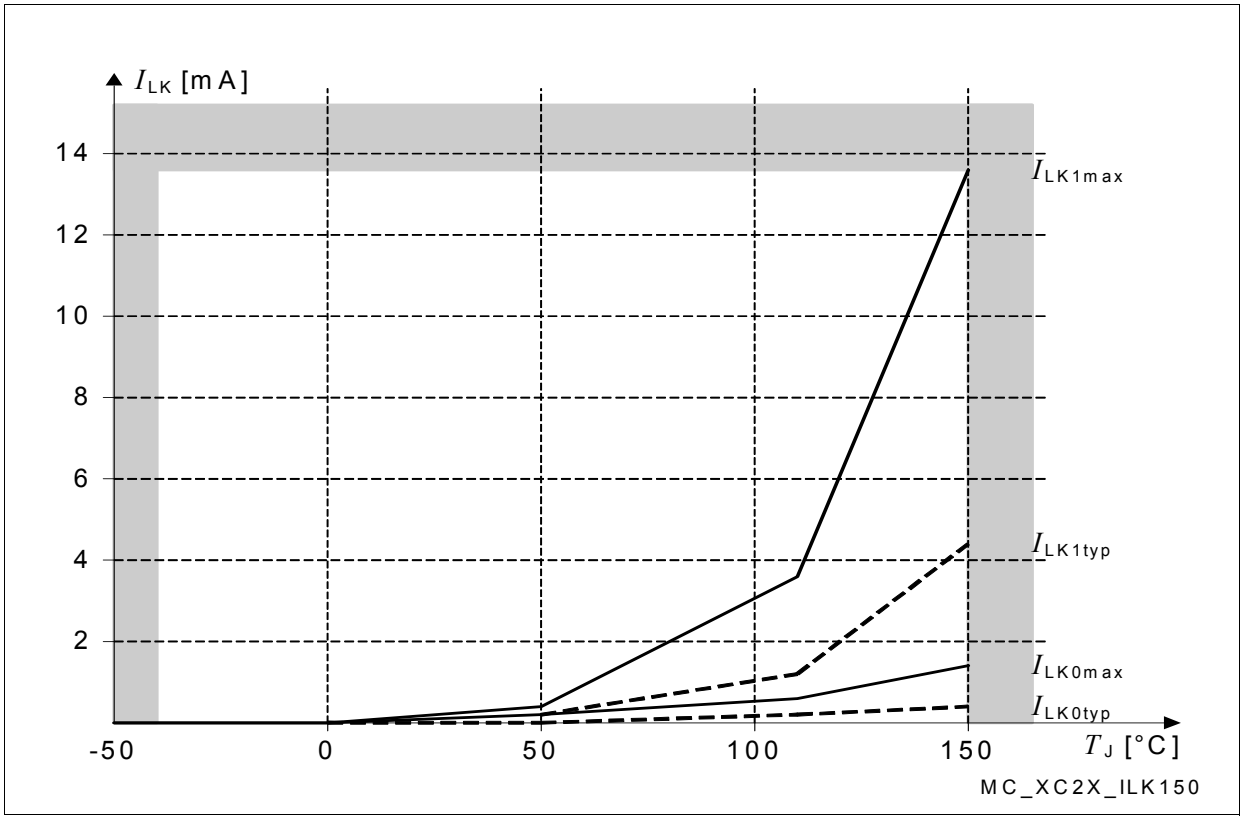

Figure 14 Leakage Supply Current as a Function of Temperature

4.6 AC Parameters

These parameters describe the dynamic behavior of the XC228x.

4.6.1 Testing Waveforms

These values are used for characterization and production testing (except pin XTAL1).

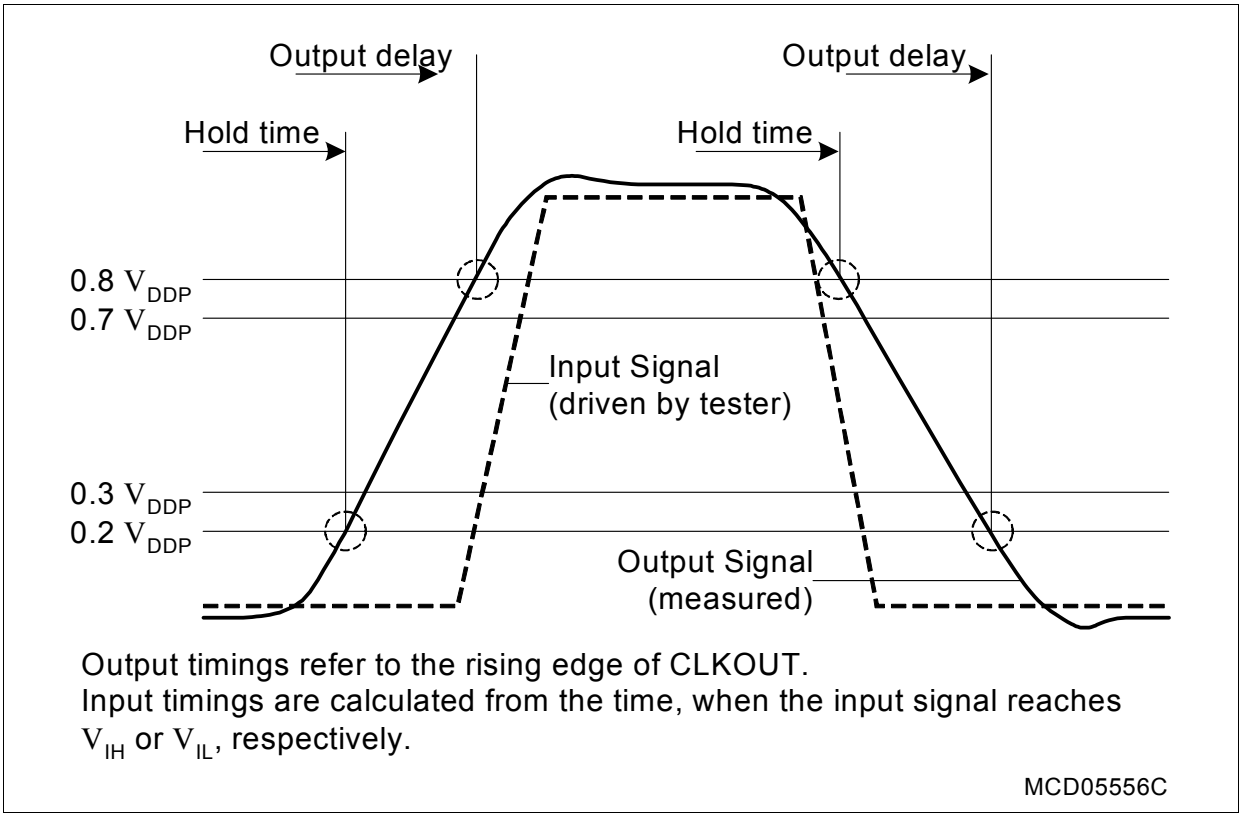

Figure 16 Input Output Waveforms

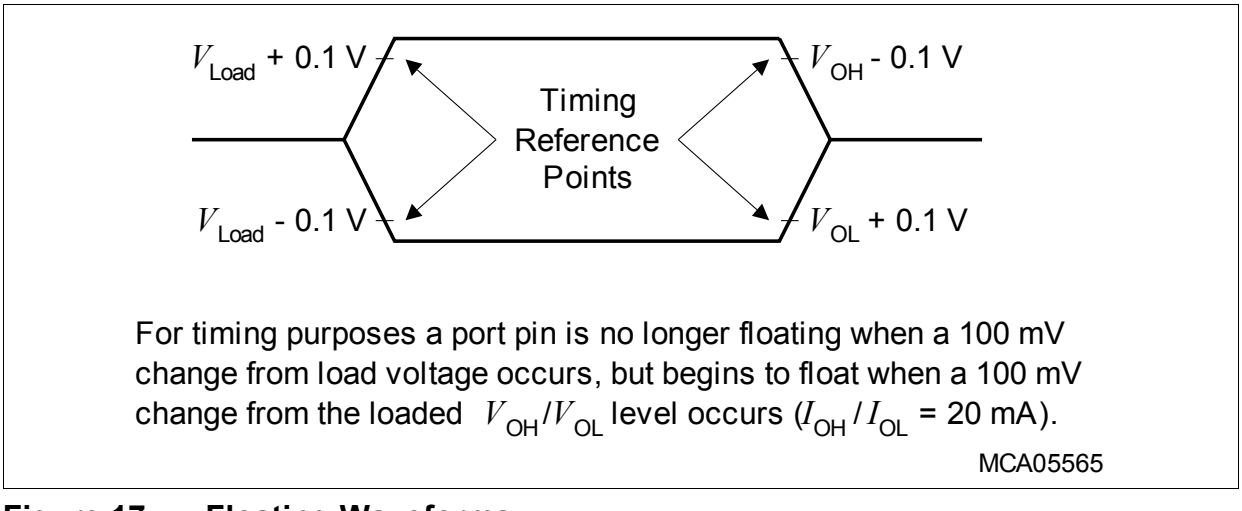

Figure 17 Floating Waveforms

Direct Drive

When direct drive operation is selected (SYSCON0.CLKSEL = 11_B), the system clock is derived directly from the input clock signal CLKIN1:

$f_{SYS} = f_{IN}$.

The frequency of f_{SYS} is the same as the frequency of f_{IN}. In this case the high and low times of f_{SYS} are determined by the duty cycle of the input clock f_{IN}.

Selecting Bypass Operation from the XTAL1[1)] input and using a divider factor of 1 results in a similar configuration.

Prescaler Operation

When prescaler operation is selected (SYSCON0.CLKSEL = 10_B, PLLCON0.VCOBY = 1_B), the system clock is derived either from the crystal oscillator (input clock signal XTAL1) or from the internal clock source through the output prescaler K1 (= K1DIV+1):

$f_{SYS} = f_{OSC}$ / K1.

If a divider factor of 1 is selected, the frequency of f_{SYS} equals the frequency of f_{OSC}. In this case the high and low times of f_{SYS} are determined by the duty cycle of the input clock f_{OSC} (external or internal).

The lowest system clock frequency results from selecting the maximum value for the divider factor K1:

$f_{SYS} = f_{OSC}$ / 1024.

Phase Locked Loop (PLL)

When PLL operation is selected (SYSCON0.CLKSEL = 10_B, PLLCON0.VCOBY = 0_B), the on-chip phase locked loop is enabled and provides the system clock. The PLL multiplies the input frequency by the factor **F** ($f_{SYS} = f_{IN} \times$ **F**).
F is calculated from the input divider P (= PDIV+1), the multiplication factor N (= NDIV+1), and the output divider K2 (= K2DIV+1):
(**F** = N / (P $\times$ K2)).

The input clock can be derived either from an external source at XTAL1 or from the on-chip clock source.

The PLL circuit synchronizes the system clock to the input clock. This synchronization is performed smoothly so that the system clock frequency does not change abruptly.

Adjustment to the input clock continuously changes the frequency of f_{SYS} so that it is locked to f_{IN}. The slight variation causes a jitter of f_{SYS} which in turn affects the duration of individual TCSs.

1) Voltages on XTAL1 must comply to the core supply voltage V_{DDI1}.

Variable Memory Cycles

External bus cycles of the XC228x are executed in five consecutive cycle phases (AB, C, D, E, F). The duration of each cycle phase is programmable (via the TCONCSx registers) to adapt the external bus cycles to the respective external module (memory, peripheral, etc.).

The duration of the access phase can optionally be controlled by the external module using the READY handshake input.

This table provides a summary of the phases and the ranges for their length.

Table 28 Programmable Bus Cycle Phases (see timing diagrams)

Bus Cycle Phase	Parameter	Valid Values	Unit
Address setup phase, the standard duration of this phase (1 … 2 TCS) can be extended by 0 … 3 TCS if the address window is changed	tpAB	1 … 2 (5)	TCS
Command delay phase	tpC	0 … 3	TCS
Write Data setup/MUX Tristate phase	tpD	0 … 1	TCS
Access phase	tpE	1 … 32	TCS
Address/Write Data hold phase	tpF	0 … 3	TCS

Note: The bandwidth of a parameter (from minimum to maximum value) covers the whole operating range (temperature, voltage) as well as process variations. Within a given device, however, this bandwidth is smaller than the specified range. This is also due to interdependencies between certain parameters. Some of these interdependencies are described in additional notes (see standard timing).

4.6.6 JTAG Interface Timing

The following parameters are applicable for communication through the JTAG debug interface. The JTAG module is fully compliant with IEEE1149.1-2000.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Table 35 JTAG Interface Timing Parameters (Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK clock period	t_1 SR	60	50	–	ns	–
TCK high time	t_2 SR	16	–	–	ns	–
TCK low time	t_3 SR	16	–	–	ns	–
TCK clock rise time	t_4 SR	–	–	8	ns	–
TCK clock fall time	t_5 SR	–	–	8	ns	–
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	–
TDI/TMS hold after TCK rising edge	t_7 SR	6	–	–	ns	–
TDO valid after TCK falling edge[1]	t_8 CC	–	–	30	ns	C_L = 50 pF
	t_8 CC	10	–	–	ns	C_L = 20 pF
TDO high imped. to valid from TCK falling edge[1)2)]	t_9 CC	–	–	30	ns	C_L = 50 pF
TDO valid to high imped. from TCK falling edge[1)]	t_{10} CC	–	–	30	ns	C_L = 50 pF

1) The falling edge on TCK is used to generate the TDO timing.

2) The setup time for TDO is given implicitly by the TCK cycle time.